

IGBT3 Power Chip

Features:

- 1700V Trench & Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

• power modules

Applications:

drives



Chip Type	V _{CE}	<i>I</i> _C	Die Size	Package
SIGC158T170R3E	1700V	125A	12.57 x 12.57 mm ²	sawn on foil

Mechanical Parameters

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Raster size	12.57 x 12.57			
Emitter pad size (incl. gate pad)	4 x (5.05 x 2.32) 4 x (5.05 x 2.54)	mm²		
Gate pad size	1.12 x 1.12			
Area total	158			
Thickness	190	μm		
Wafer size	200	mm		
Max.possible chips per wafer	159			
Passivation frontside	Photoimide			
Pad metal	3200 nm AlSiCu			
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	Electrically conductive glue or solder			
Wire bond	AI, <500μm			
Reject ink dot size	Ø 0.65mm; max 1.2mm			
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C			



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	1700	V	
DC collector current, limited by $T_{\rm vj\ max}$	I _C	1)	А	
Pulsed collector current, t_p limited by $T_{vj max}$	$I_{c,puls}$	375	Α	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	T _{vj}	-40 +175	°C	
Operating junction temperature	$T_{\rm vj}$	-40+150	°C	
Short circuit data ²⁾ $V_{GE} = 15V$, $V_{CC} = 1000V$, $T_{vj} = 150$ °C	t_{SC}	10	μs	
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{C,max} = 250A, V_{CE,max} = 1700V$ $T_{vj} \le 150^{\circ}C$			

¹⁾ depending on thermal properties of assembly

Static Characteristic (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter		Conditions	min.	typ.	max.	0.111
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 3.8 mA	1700			
Collector-Emitter saturation voltage	V _{CEsat} ³⁾	V _{GE} =15V, I _C =125A	1.6	2	2.4	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =6mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.2	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V _{CE} =1700V , V _{GE} =0V			6.9	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			600	nA
Integrated gate resistor	$r_{\rm G}$			5		Ω

³⁾ Vcesat tested at lower current

Dynamic Characteristic (not subject to production test - verified by design / characterization), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Linit
Parameter	Symbol	Conditions	min.	typ.	max.	Unit
Input capacitance	Cies	$V_{\text{CE}} = 25 \text{V},$ $V_{\text{GE}} = 0 \text{V},$ $f = 1 \text{MHz}$		11001		
Reverse transfer capacitance	C _{res}			365		pF

²⁾ not subject to production test - verified by design/characterization

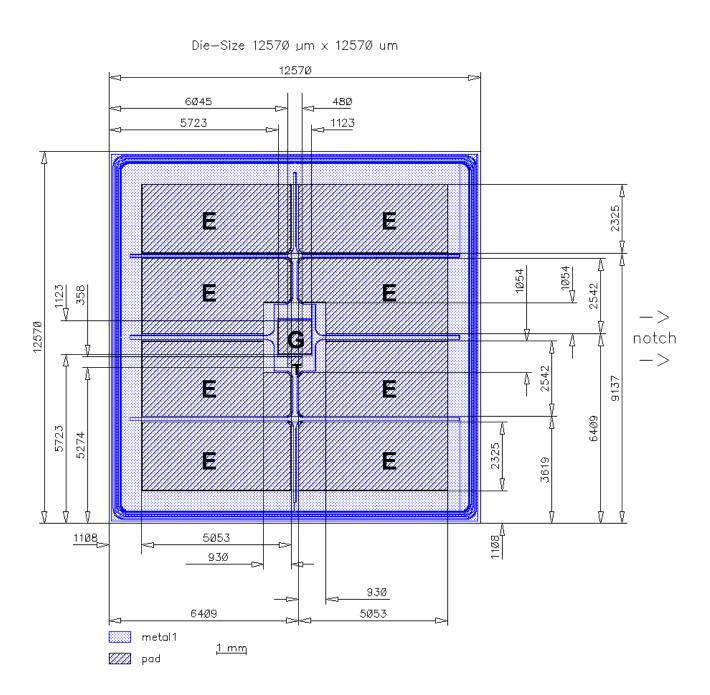


Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter

G = Gate

T = Test pad do not contact



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date	
2.1	Change wafer size to 200 mm	14.04.2010	
2.2	Additional basic types L7801M, L7801T, L7801E	01.07.2014	

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